

300	<b>PARTICLE PRECESSION RESONANCE</b>	334	..With separate pickup
301	..Using a magnetometer	335	...Employing multiple frequencies
302	..To determine direction	336	...To detect transient signals
303	..Using well logging device	337	...To detect return wave signals
304	..Using optical pumping or sensing device	338	...Within a borehole
305	..Having particular optical cell structure	339	....By induction logging
306	..Determine fluid flow rate	340	.....To measure susceptibility
307	..Using a nuclear resonance spectrometer system	341	.....To measure dielectric constant
308	..Including a test sample and control sample	342	.....Using a toroidal coil
309	..To obtain localized resonance within a sample	343	.....Using angularly spaced coils
310	..By scanning sample frequency spectrum	344	..With radiant energy or nonconductive-type receiver
311	..With signal decoupling	345	..By magnetic means
312	..By spectrum storage and analysis	346	..Within a borehole
313	..Including polarizing magnetic field/radio frequency tuning	347	..Using electrode arrays, circuits, structure, or supports
314	..With conditioning of transmitter signal	348	..For detecting naturally occurring fields, currents, or potentials
315	..With sample resonant frequency and temperature interdependence	349	...Of the telluric type
316	..Using an electron resonance spectrometer system	350	...Including magneto-telluric type
317	..Including a test sample and control sample	351	...Within a borehole
318	..Spectrometer components	352	...Combined with artificial source measurement
319	..Polarizing field magnet	353	...With fluid movement or pressure variation
320	..With homogeneity control	354	..Coupled to artificial current source
321	..Sample holder structure	355	...Within a borehole
322	..Electronic circuit elements	356	...While drilling
323	<b>OF GEOPHYSICAL SURFACE OR SUBSURFACE IN SITU</b>	357	...Including separate pickup of generated fields or potentials
324	..Including borehole fluid investigation	358	...With three electrodes
325	..To determine fluid entry	359	...With nonelectrode pickup means
326	..For small object detection or location	360	...Using a pulse-type current source
327	..Using oscillator coupled search head	361	....With mechanical current reversing means
328	...Of the beat frequency type	362	.....To measure induced polarization
329	..Using movable transmitter and receiver	363	....By varying the path of current flow
330	..By aerial survey	364	.....Using frequency variation
331	..For magnetic field detection	365	....Offshore
332	..With radiant energy or nonconductive-type transmitter	366	....For well logging
333	..Within a borehole	367	....Using a pad member
		368	....Cased borehole
		369	....While drilling

370	.....Using surface current electrodes	404	.Cathode-ray tube
371	.....Using plural fields	405	.Vacuum tube
372	.....Between spaced boreholes	406	..Plural tubes in the testing circuit
373	.....Using current focussing means	407	..Testing circuit for diverse-type tube
374	.....Including a pad member	408	..Circuit for making diverse test
375	.....Including plural current focussing arrays	409	..Testing discharge space characteristic (e.g., emission)
376	<b>OF SUBSURFACE CORE SAMPLE</b>	410	...With application of current or potential to the discharge control means
377	.For magnetic properties	411	....Pulsating or alternating current or potential for the discharge control means
378	<b>INTERNAL-COMBUSTION ENGINE IGNITION SYSTEM OR DEVICE</b>	412	.....Pulsating or alternating current for the anode
379	.With analysis of displayed waveform	413	..Shock testing
380	.Electronic ignition system	414	.Electric lamp
381	..With magnetically controlled circuit	415	<b>ELECTROMECHANICAL SWITCHING DEVICE</b>
382	..With capacitor discharge circuit	416	.Voltage regulator
383	.By simulating or substituting for a component under test	417	.Thermostat switch
384	.Using plural tests in a conventional ignition system	418	.Relay
385	.Distributor	419	..Reed switch
386	..Dwell (i.e., cam angle)	420	..To evaluate contact chatter
387	..Condenser	421	..To evaluate contact resistance
388	.Coil	422	..To evaluate contact sequence of operation
389	.Magneto	423	..To evaluate contact response time
390	.Low or high tension lead	424	.Circuit breaker
391	.Ignition timing	425	<b>ELECTROLYTE PROPERTIES</b>
392	..Using a pulse signal technique	426	.Using a battery testing device
393	.In situ testing of spark plug	427	..To determine ampere-hour charge capacity
394	..With cathode-ray tube display	428	...Including an integrating device
395	..Using an illuminating device to indicate spark plug condition	429	..To determine load/no-load voltage
396	..With an air gap in series with spark plug to indicate spark plug condition	430	..To determine internal battery impedance
397	..By shorting the plug to ground to indicate spark plug condition	431	..With temperature compensation of measured condition
398	..With air gap in ground circuit	432	..To determine battery electrolyte condition
399	..Wherein a measured electric quantity indicates spark plug condition	433	..To compare battery voltage with a reference voltage
400	.Spark plug removed or tested in a test fixture	434	..To determine plural cell condition
401	..Using a pressure chamber	435	..Having particular meter scale or indicator
402	.Apparatus for coupling a measuring instrument to an ignition system		
403	<b>ELECTRIC LAMP OR DISCHARGE DEVICE</b>		

436	..Including oscillator in measurement circuit	204	.Fluid material examination
437	..Including probe structure	205	.Permanent magnet testing
438	.Using a pH determining device	206	.Movable random length material measurement
439	.Using a conductivity determining device	207.11	.Displacement
440	..Which includes a dropping mercury cell	207.12	..Compensation for measurement
441	..Which includes a temperature responsive element	207.13	..Having particular sensor means
442	..Which includes an oscillator	207.14	...Diverse sensors
443	..Having a bridge circuit	207.15	...Inductive
444	..Which includes current and voltage electrodes	207.16	....Electrically energized
445	..Having inductance probe structure	207.17	.....Separate pick-up
446	..Having conductance probe structure	207.18	....Differential type (e.g., LVDT)
447	...With movable or adjustable electrode	207.19	....Differential bridge circuit
448	...With concentric electrodes	207.2	...Hall effect
449	...With axially arranged electrodes	207.21	...Magnetoiresistive
450	..Which includes particular cell container structure	207.22	..Having particular sensed object
451	<b>A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON</b>	207.23	..Plural measurements (e.g., linear and rotary)
452	<b>A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON</b>	207.24	..Linear
453	.In a liquid	207.25	..Rotary
454	.Frictionally induced	207.26	..Approach or retreat
455	.Corona induced	209	.Stress in material measurement
456	.For flaw detection	210	.Magnetic information storage element testing
457	<b>ELECTROSTATIC FIELD</b>	211	..Memory core storage element testing
458	.Using modulation-type electrometer	212	..Dynamic information element testing
459	<b>USING IONIZATION EFFECTS</b>	213	.Magnetic recording medium on magnetized object records object field
460	.For monitoring pressure	214	.By paramagnetic particles
461	..Using a radioactive substance	215	..With pattern enhancing additive
462	..Using thermionic emissions	216	..Flaw testing
463	..Using a magnetic field	217	.Railroad rail flaw testing
464	.For analysis of gas, vapor, or particles of matter	218	..Rail joint cutout
465	..Using electronegative gas sensor	219	.Magnetic sensor within material
466	..Using a filter	220	..Sensor supported, positioned, or moved within pipe
467	..Using test material desorption	221	...Borehole pipe testing
468	..Using thermal ionization	222	.Hysteresis or eddy current loss testing
469	..Using a radioactive substance	223	.Hysteresis loop curve display or recording
470	..Using thermionic emission	224	.With temperature control of material or element of test circuit
200	<b>MAGNETIC</b>	225	.With compensation for test variable
201	.Susceptibility	226	.Combined
202	.Calibration	227	.Plural tests
203	.Curie point determination	228	.With means to create magnetic field to test material

229	..Thickness measuring	503	.In vehicle wiring
230	...Layer or layered material	504	..With trailer
231	..With backing member	505	..Combined with window glass
232	..Plural magnetic fields in material	506	.Combined with a flashlight
233	..With phase sensitive element	507	..With fuse testing attachment
234	..Electrically energized nonforce type sensor	508	.With electric power receptacle for line wire testing
235	...Noncoil type	509	.Of ground fault indication
236	...Oscillator type	510	..Of electrically operated apparatus (power tool, appliance, machine, etc.)
237	...Material flaw testing	511	.Of electrically operated apparatus (power tool, appliance, machine, etc.)
238	..Material flaw testing	512	.For fault location
239	..Induced voltage-type sensor	513	..Where component moves while under test
240	..Material flaw testing	514	...By exposing component to liquid or gas while under test
241	...Opposed induced voltage sensors	515	...Using a particular sensing electrode
242	...Plural sensors	516	...Metal chain
243	...Plural sensors	517	...Wire bristles
244	.Magnetometers	518	...Metal pellets or beads
244.1	..Optical	519	..By capacitance measuring
245	..Plural sensor axis misalignment correction	520	..By frequency sensitive or responsive detection
246	..With means to align field sensor with magnetic field sensed	521	..By phase sensitive or responsive detection
247	..Nonparallel plural magnetic sensors	522	..By voltage or current measuring
248	..Superconductive magnetometers	523	...Of an applied test signal
249	..Thin film magnetometers	524	...Polarity responsive
250	..Electronic tube or microwave magnetometers	525	..By resistance or impedance measuring
251	..Hall plate magnetometers	526	...Using a bridge circuit
252	..Semiconductor type solid-state or magnetoresistive magnetometers	527	..By applying a test signal
253	..Saturable core magnetometers	528	...Tracing test signal to fault location
254	...Second harmonic type	529	...Using a magnetic field sensor
255	...Peak voltage type	530	...Using an electric field sensor
256	..Energized movable sensing coil magnetometers	531	...At fault site
257	..Moving coil magnetometer	532	...Using time measuring
258	..Fixed coil magnetometer	533	...Of reflected test signal
259	..Movable magnet or magnetic member interacts with magnetic field	534	..By reflection technique
260	.Magnetic field detection devices	535	..By time measuring
261	..With support for article	536	..By spark or arc discharge
262	.Magnetic test structure elements	537	.Of individual circuit component or element
263	.Current through test material forms test magnetic field	750.01	..Measurement or control of test condition
500	<b>FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS</b>	750.02	...Calibration of test equipment
501	.Using radiant energy	750.03	...Thermal preconditioning or temperature control
502	.In an ignitor or detonator		

750.04	....Thermal matching of guidance member	754.15	.....Fluid pressure
750.05	....Burn-in	754.16	.....Chamber or bladder
750.06	.....With temperature sensing	754.17	.....Magnetic means
750.07	.....With feedback control	754.18	....With interpose
750.08	....By fluid	754.19	....With recording of test result
750.09	....By heat sink	754.2	....Penetrative
750.1	.....With biasing means	754.21	...Non-contact probe
750.11	....Thermoelectric	754.22	....Electron beam
750.12	....Electromagnetic	754.23	....Optical beam
750.13	....Of test device transporting means	754.24	....With plasma probe
750.14	..Environmental control	754.25	....Ultrasonic
750.15	..With identification on device under test (DUT)	754.26	....Tunnel current probe
750.16	..Relative positioning or alignment of device under test and test structure	754.27	....Electrical field
750.17	...By capacitive means	754.28	....Capacitive coupling
750.18	...By information on device under test	754.29	....Magnetic field
750.19	...Adjustable support for device under test	754.3	....Intermolecular
750.2	....Vacuum support	754.31	....Radio wave
750.21	....Magnetic support	755.01	..Probe structure
750.22	...Testing device mounted for multi-directional movement	755.02	...Coaxial
750.23	...Using optical means	755.03	...Rigid
750.24	...By electrical contact means	755.04	...Force absorption
750.25	...By mechanical means	755.05	....Spring
750.26	..Shielding or casing of device under test or of test structure	755.06	....Buckling
750.27	...EMI interference	755.07	...Cantilever
750.28	...Temperature effect	755.08	...Elastomeric
750.29	...Mechanical effect	755.09	...Membrane
750.3	..Built-in test circuit	755.1	...Dendritic structure
754.01	..Test probe techniques	755.11	...Elongated pin or probe
754.02	...Hand-held	756.01	..Support for device under test or test structure
754.03	...Contact probe	756.02	...DUT socket or carrier
754.04	....Liquid state	756.03	...Probe card
754.05	....Kelvin probe	756.04	...Pin fixture
754.06	....Waveguide probe	756.05	...With electrical connectors
754.07	....Probe or probe card with build-in circuit element	756.06	...With impedance matching
754.08	....In or on support for device under test	756.07	...Board or plate
754.09	....Carrier feature	757.01	..Transporting or conveying the device under test to the testing station
754.1	....Probe contact confirmation	757.02	...Printed circuit board
754.11	....Probe contact enhancement or compensation	757.03	...Wafer
754.12	....Biasing means	757.04	...Packaged IC or unpackaged die or dice
754.13	.....Mechanical	757.05	...Multiple chip module
754.14	.....Spring	758.01	..Cleaning probe or device under test
		758.02	...By laser ablation
		758.03	...By blowing air
		758.04	...By scraping
		758.05	...By chemical means
		759.01	..After-test activity
		759.02	...Marking tested objects
		759.03	...Sorting tested objects
		760.01	..Test of liquid crystal device

760.02	...Thin film transistor type (TFT)	603	..For excitation
		604	...Including marker signal generator circuit
761.01	..Test of solar cell		
762.01	..Test of semiconductor device	605	..For response signal evaluation or processing
762.02	...Packaged integrated circuits		
762.03	...Integrated circuit die	606	...Including a signal comparison circuit
762.04	...TAB carrier		
762.05	...Semiconductor wafer	607	...Including a conversion (e.g., A->D or D-> A) process
762.06	...Multiple chip module		
762.07	...Diode	608	...Including a ratiometric function
762.08	...Bipolar transistor		
762.09	...Field effect transistor	609	..For sensing
762.1	...With barrier layer	610	...Including a bridge circuit
763.01	..Printed circuit board	611	...Including a remote type circuit
763.02	...Both sides		
764.01	..Power supply	612	.Parameter related to the reproduction or fidelity of a signal affected by a circuit under test
765.01	..Motor or generator fault		
538	..Electrical connectors		
539	..Multiconductor cable		
540	...With sequencer	613	..Noise
541	...For insulation fault	614	...Signal to noise ratio or noise figure
542	...Having a light or sound indicator	615	..Transfer function type characteristics
543	..Single conductor cable		
544	...For insulation fault	616	...Gain or attenuation
545	..Armature or rotor	617	...Response time or phase delay
546	..Winding or coil	618	...Transient response or transient recovery time (e.g., damping)
547	...Transformer		
548	..Capacitor		
549	..Resistor	619	...Selective type characteristics
550	..Fuse	620	..Distortion
551	..Insulation	621	...Envelope delay
552	...Bushing	622	...Phase
553	...Oil	623	...Harmonic
554	...Sheet material	624	...Intermodulation
555	..Instruments and devices for fault testing	625	...Dissymmetry or asymmetry
		626	...Nonlinearity
556	..Having a lamp or light indicator	627	..Shielding effectiveness (SE)
		628	...Circuit interference (e.g., crosstalk) measurement
557	<b>FOR INSULATION FAULT OF NONCIRCUIT ELEMENTS</b>	629	.Distributive type parameters
558	..Where element moves while under test	630	..Plural diverse parameters
		631	..Using wave polarization (e.g., field rotation)
559	..Where a moving sensing electrode scans a stationary element under test	632	..Using particular field coupling type (e.g., fringing field)
600	<b>IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS</b>	633	..Using resonant frequency
		634	...To determine water content
		635	...To determine dimension (e.g., distance or thickness)
601	..Calibration	636	...With a resonant cavity
602	..With auxiliary means to condition stimulus/response signals	637	..Using transmitted or reflected microwaves

638	...Scattering type parameters (e.g., complex reflection coefficient)	672	....By comparison or difference circuit
639	...Where energy is transmitted through a test substance	673	.....Including a bridge circuit
640	....To determine water content	674	...By frequency signal response, change or processing circuit
641	....To determine insertion loss	675	.....Including a tuned or resonant circuit
642	...Where energy is reflected (e.g., reflectometry)	676	...With pulse signal processing circuit
643	....To determine water content	677	...Including R/C time constant circuit
644	....To determine dimension (e.g., distance or thickness)	678	...Including charge or discharge cycle circuit
645	....Having standing wave pattern	679	...With comparison or difference circuit
646	....To determine reflection coefficient	680	...Including a bridge circuit
647	..Using a comparison or difference circuit	681	..With frequency signal response, change or processing circuit
648	..With a bridge circuit	682	...Including a tuned or resonant circuit
649	..Lumped type parameters	683	...With phase signal processing circuit
650	..Using phasor or vector analysis	684	...With compensation means
651	...With a bridge circuit	685	....For temperature variation
652	..Of a resonant circuit	686	...With a capacitive sensing means
653	..For figure of merit or Q value	687	...Having fringing field coupling
654	..Using inductive type measurement	688	...Including a guard or ground electrode
655	...Including a tuned or resonant circuit	689	....To determine water content
656	...Including a comparison or difference circuit	690	...Including a probe type structure
657	....Using a bridge circuit	691	..Using resistance or conductance measurement
658	..Using capacitive type measurement	692	...With living organism condition determination using conductivity effects
659	...With loss characteristic evaluation	693	...With object or substance characteristic determination using conductivity effects
660	...With variable electrode area	694	....To determine water content
661	...With variable distance between capacitor electrodes	695	....Where the object moves while under test
662	....To determine dimension (e.g., thickness or distance)	696	....With a probe structure
663	...Where a material or object forms part of the dielectric being measured	697	....For interface
664	....To determine water content	698	....To determine oil qualities
665	....By comparison or difference circuit	699	....To determine dimension (e.g., distance or thickness)
666	.....Including a bridge circuit	700	....Including corrosion or erosion
667	....By frequency signal response, change or processing circuit	701	...Where the object moves while under test
668	.....Including a tuned or resonant circuit	702	...With radiant energy effects
669	.....With compensation means		
670	.....For temperature variations		
671	....To determine dimension (e.g., dielectric thickness)		

703	....Including heating	163	.Including speed analog electrical signal generator
704	..With ratio determination		
705	..With comparison or difference circuit	164	..Eddy current generator type (e.g., tachometer)
706	....Including a bridge circuit	165	..With direction indicator
707	..With frequency response, change or processing circuit	166	.Including speed-related frequency generator
708	....Including a tuned or resonant circuit	167	..Including rotating magnetic field actuated indicator
709	..With phase signal processing circuit	168	..Including periodic switch
710	..With pulse signal processing circuit	169	...In ignition system
711	....Including R/C time constant circuit	170	...High voltage speed signal type
712	....Including a digital or logic circuit	171	...With extent-of-travel indicator
713	..With voltage or current signal evaluation	172	..Including synchronized recording medium
714	....Including a potentiometer	173	..Including magnetic detector
715	....Including a particular probing technique (e.g., four point probe)	174	...Permanent magnet type
716	.....To determine dimension (e.g., distance or thickness)	175	..Including radiant energy detector
717	.....To determine material composition	176	.Including object displacement varied variable circuit impedance
718	.....To detect a flaw or defect	177	.Including motor current or voltage sensor
719	..With semiconductor or IC materials quality determination using conductivity effects	178	.Including "event" sensing means
720	..With compensation means	179	..Magnetic field sensor
721	....For temperature variation	180	..Mechanically actuated switch
722	..Device or apparatus determines conductivity effects	71.1	<b>DETERMINING NONELECTRIC PROPERTIES BY MEASURING ELECTRIC PROPERTIES</b>
723	....Potentiometer	71.2	.Erosion
724	....Using a probe type structure	71.3	.Beam of atomic particles
725	.Using a particular bridge circuit	71.4	.Particle counting
726	.Transformer testing (e.g., ratio)	71.5	.Semiconductors for nonelectrical property
727	.Piezoelectric crystal testing (e.g., frequency, resistance)	71.6	.Superconductors
66	<b>CONDUCTOR IDENTIFICATION OR LOCATION (E.G., PHASE IDENTIFICATION)</b>	72	<b>TESTING POTENTIAL IN SPECIFIC ENVIRONMENT (E.G., LIGHTNING STROKE)</b>
67	.Inaccessible (at test point) conductor (e.g., buried in wall)	72.5	.Voltage probe
160	<b>ELECTRICAL SPEED MEASURING</b>	73.1	<b>PLURAL, AUTOMATICALLY SEQUENTIAL TESTS</b>
161	.Speed comparing means	74	<b>TESTING AND CALIBRATING ELECTRIC METERS (E.G., WATT-HOUR METERS)</b>
162	.With acceleration measuring means	75	.By stroboscopic means
		76.11	<b>MEASURING, TESTING, OR SENSING ELECTRICITY, PER SE</b>
		76.12	.Analysis of complex waves
		76.13	..Amplitude distribution
		76.14	...Radiometer (e.g., microwave, etc.)
		76.15	...With sampler

76.16	...With counter	76.67	....With space discharge device
76.17	...With integrator	76.68	...With filtering
76.18	...With slope detector	76.69	...Current output proportional to frequency
76.19	..Frequency spectrum analyzer	76.71	...Nulling circuit
76.21	...By Fourier analysis	76.72	...Qualitative output
76.22	...Real-time spectrum analyzer	76.73	...With saturable device
76.23	...With mixer	76.74	...Deviation measurement
76.24	...With sampler	76.75	..Having inductive sensing
76.25	...With slope detector	76.76	..With space discharge device
76.26	...Scanning-panoramic receiver	76.77	.Phase comparison (e.g., between cyclic pulse voltage and sinusoidal current, etc.)
76.27	....With particular sweep circuit	76.78	..Quadrature sensing
77.11	...Nonscanning	76.79	..Feedback control, electrical
76.28	....Digital filter	76.81	..Feedback control, mechanical
76.29	....With filtering	76.82	..Digital output
76.31	.....Parallel filters	76.83	..Analog output
76.32	.....With space discharge device	84	..With waveguide (e.g., coaxial cable)
76.33	....Correlation	85	..With frequency conversion
76.34	.....With space discharge device	86	..Polyphase (e.g., phase angle, phase rotation or sequence)
76.35	....With delay line	87	..With nonlinear device (e.g., saturable reactor, rectifier), discharge device (e.g., gas tube) or lamp
76.36	....With optics	88	...Cathode ray
76.37	.....Bragg cell	89	...Space discharge control means (e.g., grid)
76.38	..With sampler	90	..Electrodynamometer instrument
76.39	.Frequency of cyclic current or voltage (e.g., cyclic counting etc.)	91	..Synchroscope type
76.41	..Frequency comparison, (e.g., heterodyne, etc.)	92	.Fluid (e.g., thermal expansion)
76.42	...With sampler	93	..Conductive field (e.g., mercury)
76.43	...With plural mixers	94	...Electrolytic
76.44	...With filtering	95	.With waveguide or long line
76.45	....Bandpass	96	.Using radiant energy
76.46	....Plural	97	..Light beam type (e.g., mirror galvanometer, parallax-free scale)
76.47	...Digital output	98	.Balancing (e.g., known/unknown voltage comparison, bridge, rebalancing)
76.48	....With counter	99 R	..Automatic
76.49	..Tuned mechanical resonator (e.g., reed, piezocrystal, etc.)	100	...With recording
76.51	..By tuning (e.g., to resonance, etc.)	99 D	...Digital voltmeters
76.52	..By phase comparison	101	.Non-rebalancing bridge
76.53	...With phase lock	102	.Transient or portion of cyclic
76.54	...With delay line	103 R	.Demand, excess, maximum or minimum (e.g., separate meters for positive and negative power, peak voltmeter)
76.55	...Digital output	104	..Thermal (e.g., actuation)
76.56	....With microwave frequency detection	103 P	..Peak voltmeters
76.57	....With tone detection		
76.58	....With sampler		
76.59	....With multiplexing		
76.61	....With memory		
76.62	....With counter		
76.63	.....Using register		
76.64	.....Plural		
76.65	....With space discharge device		
76.66	...With capacitive energy storage		

- |       |  |        |  |
|-------|--|--------|--|
| 105   | .Thermal (e.g., compensation)  | 134    | .With commutator or reversing or pulsating switch (e.g., D.C. watt-hour meter) |
| 106   | ..Actuation  | 135    | ..Oscillating  |
| 107   | .Polyphase   | 136    | .With rolling wheel or ball (e.g., transmission, integrating)                  |
| 108   | ..Positive, negative or zero sequence                                      | 137    | .Eddy current rotor (e.g., A.C. integrating wattmeter)                         |
| 109   | .Electrostatic attraction or piezoelectric                                 | 138    | ..With phase adjustment  |
| 110   | .Meter protection or fraud combatting                                      | 139    | .Motor-driven, time-controlled or oscillating (e.g., ratchet)                  |
| 111   | .With storage means for voltage or current (e.g., condenser banks)         | 140 R  | .Plural inputs (e.g., summation, ratio)  |
| 112   | ..Tape, sheet (e.g., disk) or wire (e.g., magnetic) storage                | 141    | ..Voltamperes (real or reactive)   |
| 113   | .Recording   | 142    | ..Watts  |
| 114   | .Plural meters (e.g., plural movements in one case)                        | 140 D  | ..Ratio  |
| 115   | .Plural ranges, scales or registration rates                               | 143    | .Plural active motor elements (e.g., for two crossed pointers)                 |
| 116   | ..With register (e.g., discount type, demand penalty)                      | 144    | .With electromagnetic field (e.g., dynamometer)                                |
| 117 R | .Magnetic saturation (e.g., in field or in amplifier)                      | 145    | ..Solenoid plunger type  |
| 117 H | ..Hall effect  | 146    | ..With permanent magnet (e.g., field, vane)                                    |
| 118   | .Modulator/demodulator   | 147    | ..Soft iron vane   |
| 119   | .With rectifier (e.g., A.C. to D.C.)                                       | 149    | .With probe, prod or terminals   |
| 120   | .With voltage or current conversion (e.g., D.C. to A.C., 60 to 1000)       | 150    | .Eccentrically pivoted coil  |
| 121 R | .Cathode ray (e.g., magic eye)   | 151 R  | .With permanent magnet   |
| 121 E | ..Magic eye indicators   | 152    | ..Drag magnet  |
| 122   | .Gaseous discharge (e.g., spark gap voltmeter)                             | 151 A  | ..Permanent magnet core  |
| 123 R | .With amplifier or space discharge device                                  | 153    | .With register   |
| 124   | ..Inverted amplifier   | 154 R  | .With rotor (e.g., filar suspension, zero set, balancing)                      |
| 123 C | ..Feedback amplifiers  | 155    | ..With pivot (e.g., internal friction compensation, anticreep)                 |
| 125   | .Inertia control, instrument damping and vibration damping                 | 154 PB | ..Pointer and bearing details  |
| 126   | .With coupling means (e.g., attenuator, shunt)                             | 156    | .Casings   |
| 127   | ..Transformer (e.g., split core admits conductor carrying unknown current) | 157    | .Combined  |
| 128   | ..Selective filter   |        |  |
| 129   | .Polepiece (e.g., split) admits nonunitary input conductor                 |        |  |
| 130   | .Self-calibration  |        |  |
| 131   | .Suppressed zero   |        |  |
| 132   | .Nonlinear (e.g., Thyrite)   |        |  |
| 133   | .Nonquantitative (e.g., hot-line indicator, polarity tester)               |        |  |
- CROSS-REFERENCE ART COLLECTIONS**
- |     |                      |
|-----|----------------------|
| 800 | <b>DIVINING RODS</b> |
|-----|----------------------|
- FOREIGN ART COLLECTIONS**
- FOR 000 **CLASS-RELATED FOREIGN DOCUMENTS**

**FAULT DETECTING IN ELECTRIC  
CIRCUITS AND OF ELECTRIC  
COMPONENTS (324/500)**

- .Of individual circuit component  
or element(324/537)
- FOR 100 ..System sensing fields adjacent  
device under test (DUT) (324/  
750)
- FOR 101 ...Using electron beam probe  
(324/751)
- FOR 102 ...Using light probe (324/752)
- FOR 103 ...Using electro-optic device  
(324/753)

**OF GEOPHYSICAL SURFACE OR  
SUBSURFACE IN SITU (324/323)**

- .Using electrode arrays,  
circuits, structure, or  
supports (324/347)
- FOR 104 ..With probe elements (324/754)
- FOR 105 ...Internal of or on support for  
device under test (DUT): (324/  
755)
- FOR 106 ...Contact confirmation (324/756)
- FOR 107 ...Probe contact enhancement  
(324/757)
- FOR 108 ...Probe alignment or positioning  
(324/758)
- FOR 109 ...With recording of test results  
on DUT (324/759)
- FOR 110 ...With temperature control (324/  
760)
- FOR 111 ...Pin (324/761)
- FOR 112 ...Cantilever (324/762)
- FOR 113 ..DUT including test circuit  
(324/763)
- FOR 114 ..With identification of DUT  
(324/764)
- FOR 115 ..Test of semiconductor device  
(324/765)
- FOR 116 ...With barrier layer (324/766)
- FOR 117 ....Diode (324/767)
- FOR 118 ....Bipolar transistor (324/768)
- FOR 119 ....Field effect transistor (324/  
769)
- FOR 120 ..Liquid crystal device test  
(324/770)
- FOR 121 ..Power supply test (324/771)
- FOR 122 ..Motor or generator fault tests  
(324/772)
- FOR 123 **MISCELLANEOUS (324/158.1)**

